

文件编号HXA-L20-48(01)发行日期2020年06月04日

承认规格书

种类:功率电感

系列号: HXCN322520-101M

客户料号:_____

名	字户承 认栏			
承认日期	年	月	日	

(贵司承认后请签署一份返回华信安电子,谢谢!)

厦门华信安电子科技有限公司技术质量部

承 认	确认	作成
龙梅	梁峰	王亮

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Power Inductor

HXCN322520-101M

	ECN HISTORY LIST				
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN
1.0	20/06/04	新 發 行	龙梅	梁峰	王亮
備					
註					

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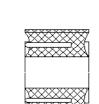
Power Inductor

HXCN322520-101M

1. Features

- 1. This specification applies Low Profile Power Inductors.
- 2. 100% Lead(Pb) & Halogen-Free and RoHS compliant.

2. Dimension



331	∢		
	<u>_</u>		
В		C	

Series	A(mm)	B(mm)	C(mm)
HXCN322520	3.2±0.3	2.5±0.3	2.0±0.3

3. Part Numbering

101 M

A: Series B: Dimension

101=100uH C: Inductance D: Inductance Tolerance M=±20%

4. Specification

ISND	Inductance	Tolerance	Test Frequency	DCR	I sat
Part Number	(uH)	(%)	(Hz)	(Ω) MAX	(A)
HXCN322520-101M	10.0	±20%	0.25V100K	6.5	0.2

Note:

 $\mbox{Isat}: \mbox{Based on inductance change} \quad (\ \triangle \mbox{L/L0}: \ \mbox{\leq-30\%$}) \ \ \mbox{@ ambient temp.} \ \mbox{25}\ \mbox{$^{\circ}$}\mbox{\subset}$

Irms : Based on temperature rise $(\triangle T : 40^{\circ}C \text{ typ.})$

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Recommendend Land pattern

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5. Material List



NO.	Items	Material	
1	Core	FH501 DRS-3.2-2.5-2.0-1.0C	
2	Wire	G1-E180Ø0.05mm*128.5Ts (REF)	
3	Ink	Halogen-Free ketone	

6. Reliability and Test Condition

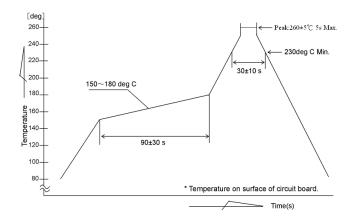
ltem	Performance	Test Method and Remarks
Operating Temperature	- 40 ~ +125℃.	Including self-generated heat
Storage Temperature	-40 ~ +85°C. - 5 to 40°C for the product with taping.	
Rated current		
Inductance (L)	Within the specified tolerance	LCR Meter: HP 4285A or equivalent, 100kHz, 1V
DC Resistance		DC Ohmmeter: HIOKI3227 or equivalent
Temperature characteristics	Inductance change: Within±20%	Measurement of inductance shall be taken at temperature rang within–25°C to +85°C. With reference to inductance value at+20 °C,change rate shall be calculated. Measurement of inductance shall be taken at temperature rang within–40°C to +125°C. With reference to inductance value at+20 °C,change rate shall be calculated.
Resistance to flexure substrate	No damage.	The test samples shall be soldered to the testing board by the reflow. As illustrated below, apply force in the direction of the arrow indicating until deflection of the test board reaches to 2mm. 20 Proced 2230 Poor Proced Proced Poor Proced Poor Proced
Adhesion of Terminal electrode	Shall not come off PC board.	The test samples shall be soldered to the testing board and by the reflow. 10 N, 5 s Applied force: 10 N to X and Y directions. Duration: 5s Solder cream thickness: 0.15
Resistance to Vibration	Inductance change: Within±10% No abnormality observed in appearance.	The test samples shall be soldered to the test board by the reflow. Then it shall be submitted to below test conditions. Frequency: 10-55Hz Total Amplitude: 1.5mm (May not exceed acceleration 196m/S2) Sweeping Method:10Hz to 55Hz to 10Hz for 1min. Time: 2 hours each in X,Y, and Z Direction. Recovery: At least 2hrs of recovery under the standard condition after the test, followed by the measurement within 48hrs.
Solderability	At least 90% of surface of terminal electrode is covered by new solder.	The test samples shall be dipped in flux, and then immersed in molten solder as shown in below. Flux: methanol solution containing rosin 25% Solder temperature: 245±5°C Time: 5±1.0 sec. Immersion depth: All sides of mounting terminal shall be immersed.

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Item	Performance		Test Method and R	emarks	
Resistance to soldering		for 40 second seconds,2 tim Test board thi	ole shall be exposed to ls, with peak temperatu les. ickness: 1.0mm aterial: glass epoxy-res	ire at 260±5°C for	
		reflow. The test samp for specified to sequence.	oles shall be soldered to oles shall be placed at ime by step 1 to step 4 ure cycles shall be rep	specified tempera as shown below	ture in
Thermal shock		Phase	Temperature(℃)	Time(min.)	
		1	-40±3℃	30±3	
		2	Room Temp	Within 3	1
		3	85±2℃	30±3	
		4	RoomTemp	Within 3	
Damp heat life test	Inductance change: Within±10% No abnormality observed in appearance.	Test Method and Remarks The test samples shall be soldered to the test board by the reflow. The test samples shall be placed in thermostatic oven set specified temperature and humidity as shown in below. Temperature: 60±2°C Humidity: 90–95%RH Time: 500+24/-0 hrs			
Loading under damp heat life test		reflow. The test samp specified temp current contin Temperature: Humidity: 90~	-95%RH nt: Rated current	thermostatic oven and applied the ra	set at
Low temperature life test		reflow.	-40±2°C		-
Loading at high temperature life test		reflow. Temperature:	nt: Rated current	o the test board b	y the

7. Soldering

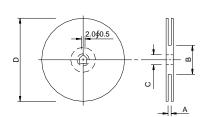


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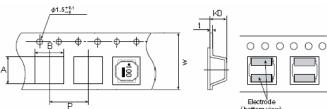
(2) Tape Dimension

8. Packaging Information

(1) Reel Dimension







Туре	A(mm)	B(mm)	C(mm)	D(mm)
HXCN322520	14±1.5	60±2.0	20±0.5	330±3.0

Туре	A(mm)	B(mm)	Ko(mm)	P(mm)	W(mm)	t(mm)
HXCN322520	6.25±0.1	6.25±0.1	4.8±0.1	12.0±0.1	16±0.3	0.3±0.1

(3) Packaging Quantity

Туре	Chip / Reel
HXCN322520	3000

Application Notice

- · Storage Conditions
- To maintain the solderability of terminal electrodes:
- 1. ISND products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- 3. Recommended products should be used within 12 months form the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.

- 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
- 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
- 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.

单击下面可查看定价,库存,交付和生命周期等信息

>>ISND(华信安)